
**Surface chemical analysis —
Determination of surface elemental
contamination on silicon wafers by
total-reflection X-ray fluorescence
(TXRF) spectroscopy**

*Analyse chimique des surfaces — Détermination de la contamination
en éléments à la surface des tranches de silicium par spectroscopie de
fluorescence X à réflexion totale*

ISO 14706:2014(E)



Reference number
ISO 14706:2014(E)

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